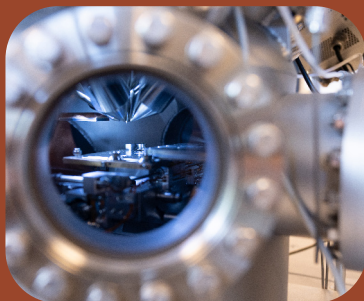
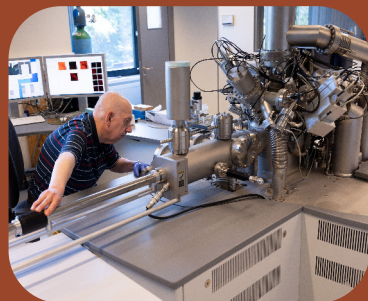


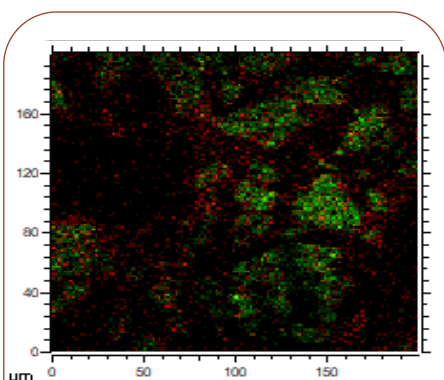


SUCH

Surface Characterization

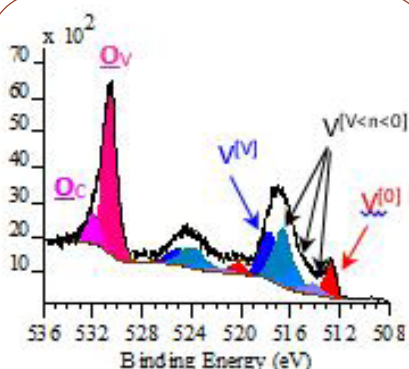
WHAT WE OFFER : SERVICES & EXPERTISE

- Characterization / tests / analysis and interpretation realized by highly qualified UCLouvain members
- Surface analysis tools (probing the first nanometers depth) in the context of material science and (bio) nanotechnology



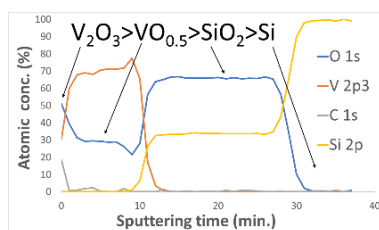
ToF-SIMS

- Solid state mass spectrometry
- 2D molecular image
- 3D depth profile



XPS

- Elemental quantification
- Chemical states
- XPS imaging and depth profile



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